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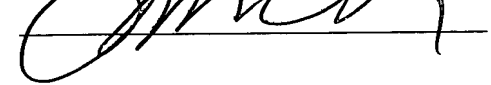
TECHNOLOGY CENTER 2800

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Jo Carter

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the Assistant Commissioner for Patents, Washington, D.C. 20231

By: 

Date: March 27, 2003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Dieter Kantz et al.
Applic. No. : 09/826,594
Filed : April 5, 2001
Title : Test Configuration for the Functional Testing
of a Semiconductor Chip
Examiner : Ernest F. Karlsen
Group Art Unit : 2829

A M E N D M E N T

Hon. Commissioner of Patents and Trademarks,
Washington, D. C. 20231

S i r :

Responsive to the Office action dated February 27, 2003 kindly
amend the above-identified application as follows:

In the Claims:

Add the following new claims:

Claim 23(new). The test configuration according to claim 20,
wherein said semiconductor chip has a functional unit for a

04/07/2003 HAHMED1 00000076 09826594

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